
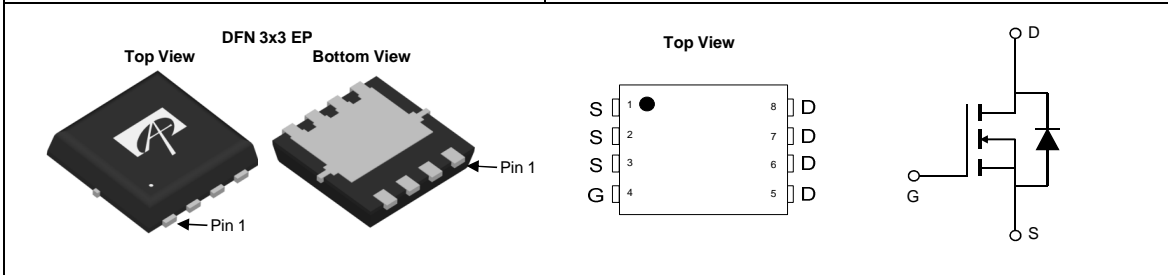


General Description	Product Summary								
<ul style="list-style-type: none"> Trench Power AlphaMOS (αMOS LV) technology Low $R_{DS(ON)}$ Low Gate Charge High Current Capability RoHS and Halogen-Free Compliant 	<table> <tr> <td>V_{DS}</td> <td>30V</td> </tr> <tr> <td>I_D (at $V_{GS}=10V$)</td> <td>12A</td> </tr> <tr> <td>$R_{DS(ON)}$ (at $V_{GS}=10V$)</td> <td>< 10.5mΩ</td> </tr> <tr> <td>$R_{DS(ON)}$ (at $V_{GS}=4.5V$)</td> <td>< 16.5mΩ</td> </tr> </table>	V_{DS}	30V	I_D (at $V_{GS}=10V$)	12A	$R_{DS(ON)}$ (at $V_{GS}=10V$)	< 10.5mΩ	$R_{DS(ON)}$ (at $V_{GS}=4.5V$)	< 16.5mΩ
V_{DS}	30V								
I_D (at $V_{GS}=10V$)	12A								
$R_{DS(ON)}$ (at $V_{GS}=10V$)	< 10.5mΩ								
$R_{DS(ON)}$ (at $V_{GS}=4.5V$)	< 16.5mΩ								
Applications <ul style="list-style-type: none"> DC/DC Converters in Computing, Servers, and POL Isolated DC/DC Converters in Telecom and Industrial 	100% UIS Tested 100% Rg Tested 								



Orderable Part Number	Package Type	Form	Minimum Order Quantity
AON7556	DFN 3x3 EP	Tape & Reel	5000

Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted			
Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	30	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current ^G	I_D	$T_C=25^\circ\text{C}$	12
		$T_C=100^\circ\text{C}$	9.4
Pulsed Drain Current ^C	I_{DM}	48	A
Continuous Drain Current ^G	I_{DSM}	$T_A=25^\circ\text{C}$	12
		$T_A=70^\circ\text{C}$	10.5
Avalanche Current ^C	I_{AS}	18	A
Avalanche energy	E_{AS}	8	mJ
V_{DS} Spike	V_{SPIKE}	36	V
Power Dissipation ^B	P_D	$T_C=25^\circ\text{C}$	12.5
		$T_C=100^\circ\text{C}$	5
Power Dissipation ^A	P_{DSM}	$T_A=25^\circ\text{C}$	4.1
		$T_A=70^\circ\text{C}$	2.6
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	$^\circ\text{C}$

Thermal Characteristics			
Parameter	Symbol	Typ	Max
Maximum Junction-to-Ambient ^A	$R_{\theta JA}$	24	30
Maximum Junction-to-Ambient ^{A D}		47	60
Maximum Junction-to-Case	$R_{\theta JC}$	8	10

Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV _{DSS}	Drain-Source Breakdown Voltage	I _D =250μA, V _{GS} =0V	30			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =30V, V _{GS} =0V T _J =55°C			1 5	μA
I _{GSS}	Gate-Body leakage current	V _{DS} =0V, V _{GS} =±20V			±100	nA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250μA	1.4	1.8	2.2	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} =10V, I _D =12A T _J =125°C		8.5	10.5	mΩ
		V _{GS} =4.5V, I _D =10A		12	14.8	
g _{FS}	Forward Transconductance	V _{DS} =5V, I _D =12A		40		S
V _{SD}	Diode Forward Voltage	I _S =1A, V _{GS} =0V		0.73	1	V
I _S	Maximum Body-Diode Continuous Current				10	A
DYNAMIC PARAMETERS						
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =15V, f=1MHz		600		pF
C _{oss}	Output Capacitance			230		pF
C _{riss}	Reverse Transfer Capacitance			30		pF
R _g	Gate resistance	f=1MHz	0.7	1.5	2.3	Ω
SWITCHING PARAMETERS						
Q _g (10V)	Total Gate Charge	V _{GS} =10V, V _{DS} =15V, I _D =12A		9	15	nC
Q _g (4.5V)	Total Gate Charge			4.4	10	nC
Q _{gs}	Gate Source Charge			1.4		nC
Q _{gd}	Gate Drain Charge			1.9		nC
t _{D(on)}	Turn-On DelayTime	V _{GS} =10V, V _{DS} =15V, R _L =1.25Ω, R _{GEN} =3Ω		5		ns
t _r	Turn-On Rise Time			2.5		ns
t _{D(off)}	Turn-Off DelayTime			17.5		ns
t _f	Turn-Off Fall Time			2.5		ns
t _{rr}	Body Diode Reverse Recovery Time	I _F =12A, dI/dt=500A/μs		8.6		ns
Q _{rr}	Body Diode Reverse Recovery Charge	I _F =12A, dI/dt=500A/μs		10.5		nC

A. The value of R_{θJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with T_A=25° C. The Power dissipation P_{DSM} is based on R_{θJA} ≤ 10s and the maximum allowed junction temperature of 150° C. The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on T_{J(MAX)}=150° C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Single pulse width limited by junction temperature T_{J(MAX)}=150° C.

D. The R_{θJA} is the sum of the thermal impedance from junction to case R_{θJC} and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of T_{J(MAX)}=150° C. The SOA curve provides a single pulse rating.

G. The maximum current rating is package limited.

H. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with T_A=25° C.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

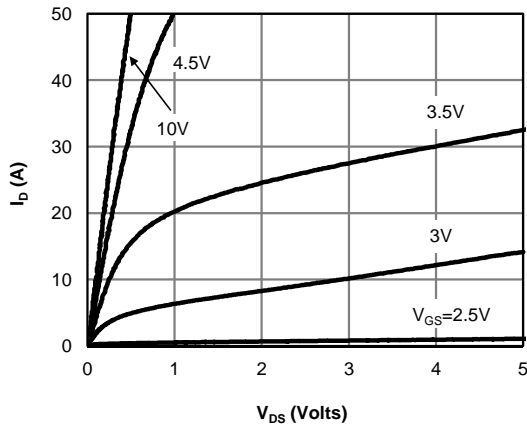


Figure 1: On-Region Characteristics (Note E)

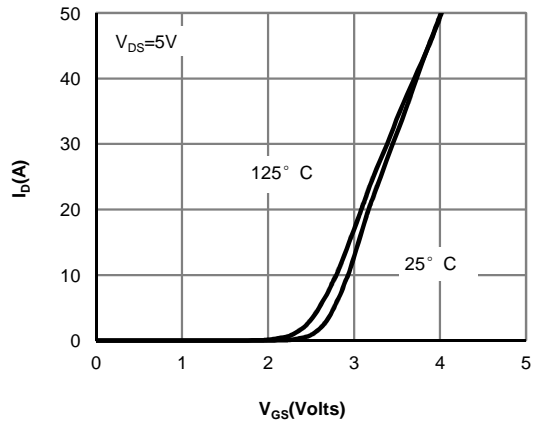


Figure 2: Transfer Characteristics (Note E)

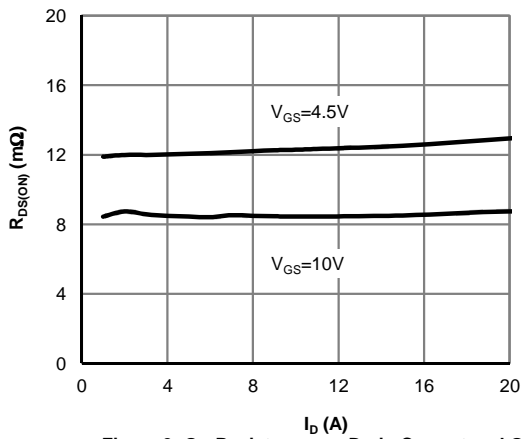


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

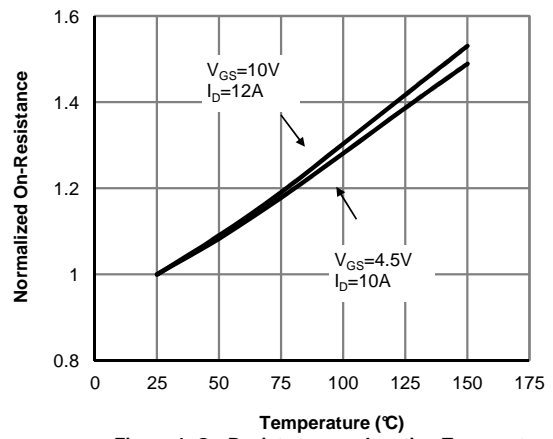


Figure 4: On-Resistance vs. Junction Temperature (Note E)

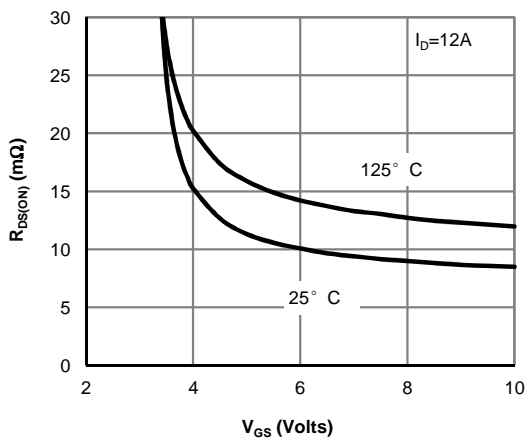


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

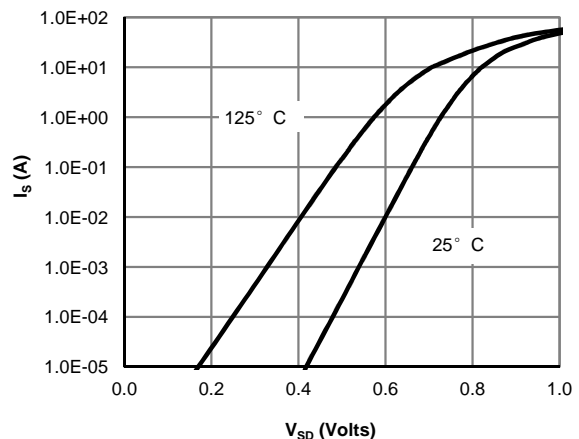


Figure 6: Body-Diode Characteristics (Note E)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

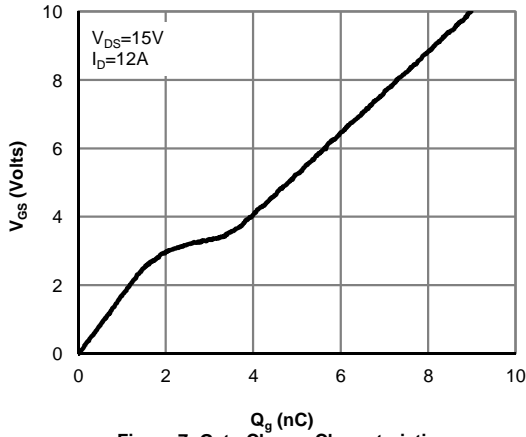


Figure 7: Gate-Charge Characteristics

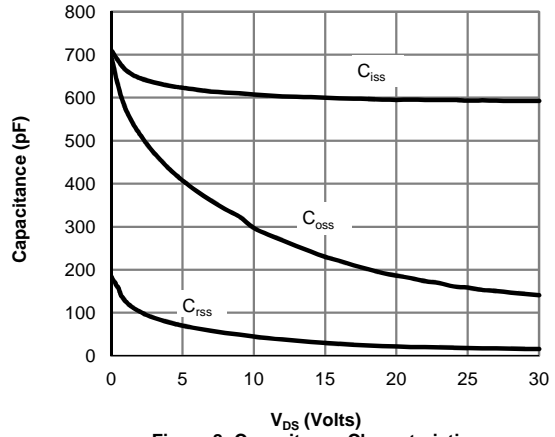


Figure 8: Capacitance Characteristics

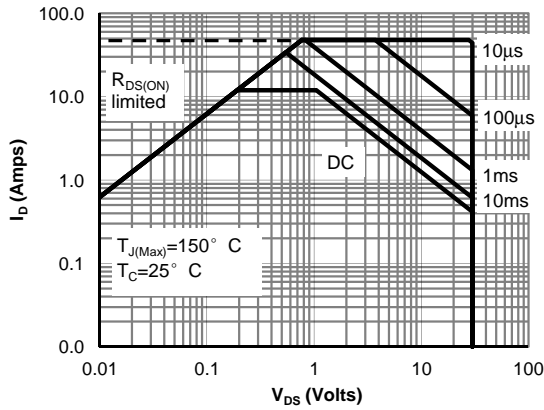


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

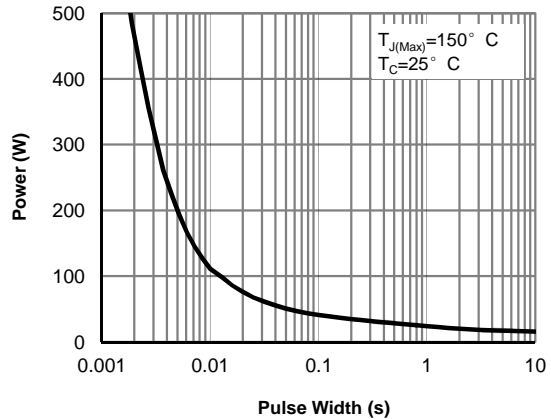


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

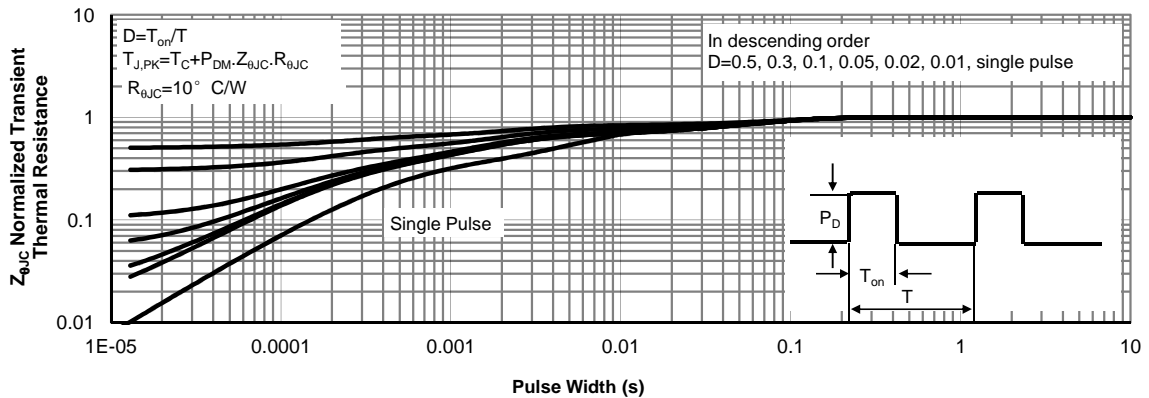


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

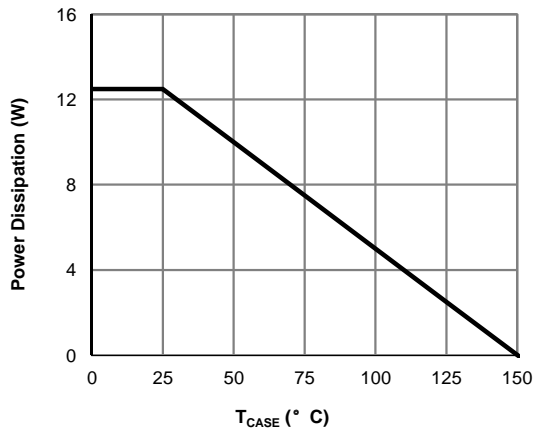


Figure 12: Power De-rating (Note F)

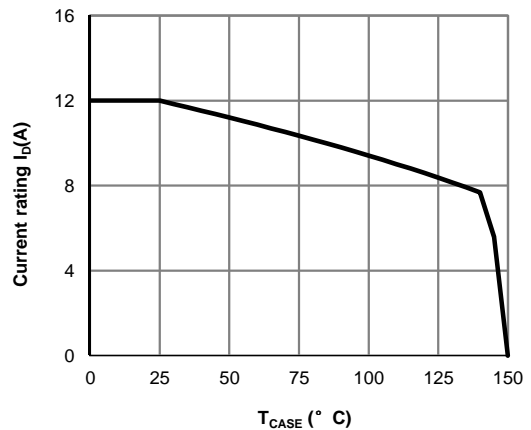


Figure 13: Current De-rating (Note F)

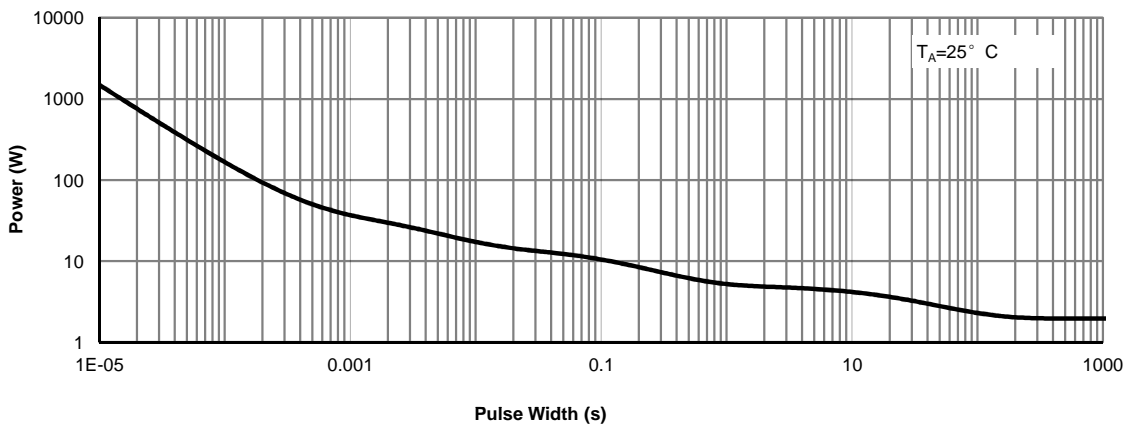


Figure 14: Single Pulse Power Rating Junction-to-Ambient (Note H)

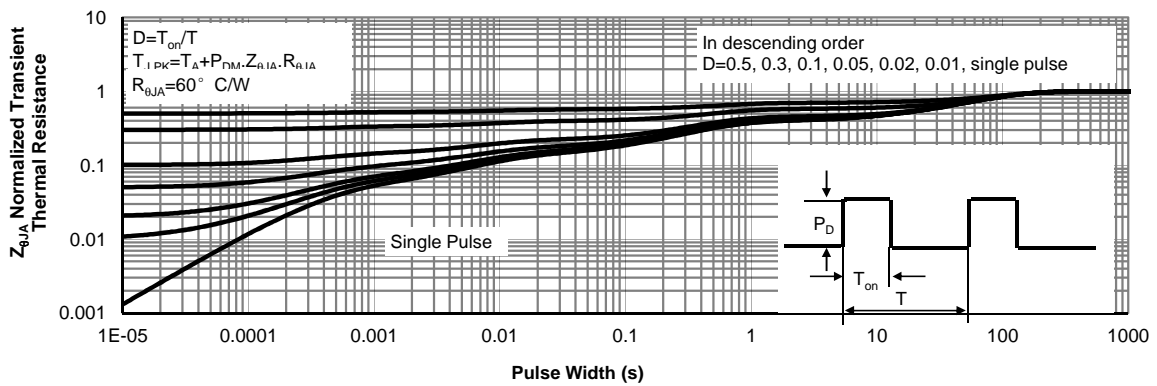
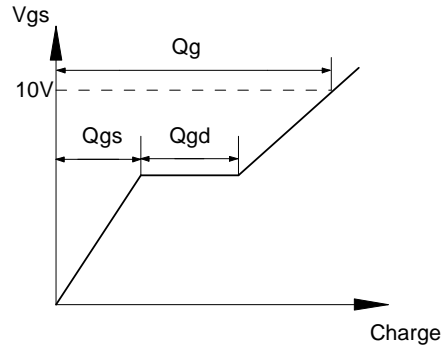
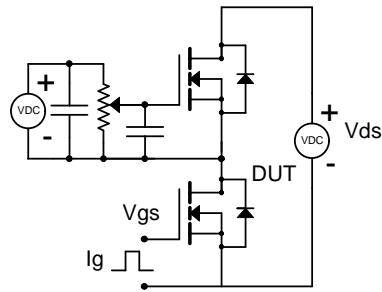
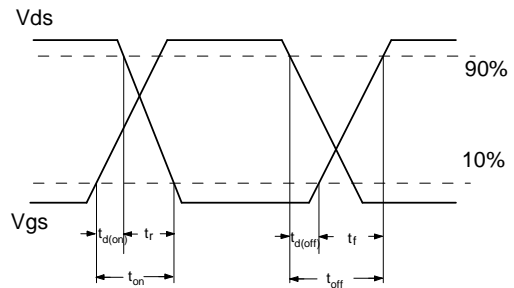
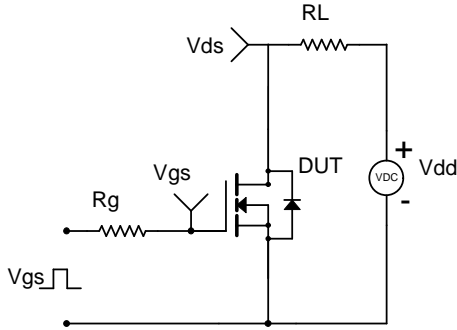


Figure 15: Normalized Maximum Transient Thermal Impedance (Note H)

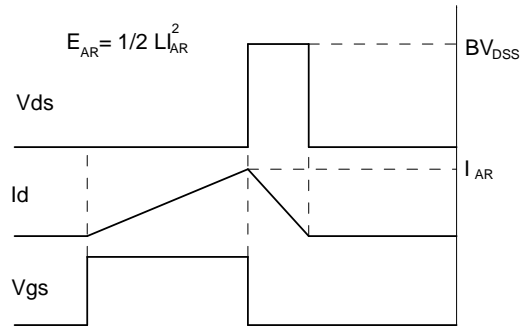
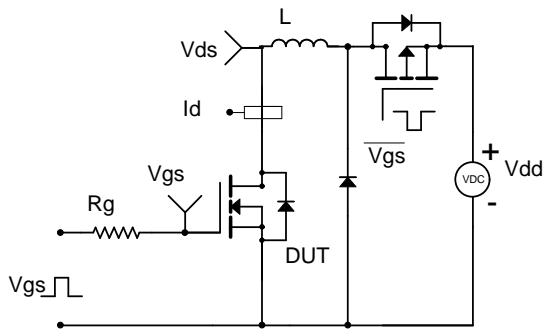
Gate Charge Test Circuit & Waveform



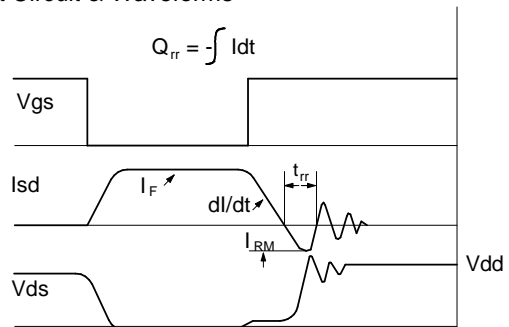
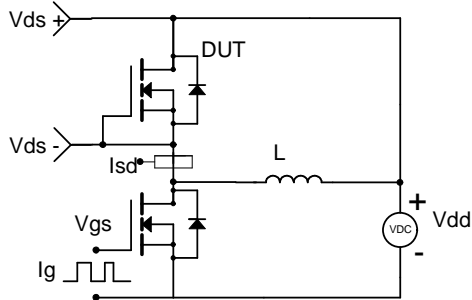
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



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